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PATENT

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant	:	Hideyuki Oshima)	Group Art Unit 2829
Serial No.	:	10/507,042)	
Filed	:	September 7, 2004)	
For	:	SEMICONDUCTOR TEST APPARATUS FOR TESTING SEMICONDUCTOR DEVICE THAT PRODUCES OUTPUT DATA BY ITS INTERNAL CLOCK TIMING)	
Examiner	:	Minh N. Tang)	

AMENDMENT

Hon. Commissioner
of Patents and Trademarks
Alexandria, VA 22313-1450

Dear Sir:

This amendment is submitted for the above-identified patent application in response to the office action from the United States Patent and Trademark Office mailed August 8, 2005. Please make the following changes.